



<b>Search Notes</b>  	Application/Control No.  10626300	Applicant(s)/Patent Under Reexamination  RICHIE ET AL.
	Examiner Kitov, Zeev	Art Unit 2836


Notes	Date	Examiner
Text search in all classes	02/13/2006	
Cross reference search	02/13/2006	ZK
Updated search	06/29/2006	ZK
Obtained translation of japanese documents	09/19/2006	ZK
Updated search	09/19/2006	ZK
U.S. Patent and Trademark Office		Part of Paper No.:



<p style="text-align: center;"><b>Searched</b></p> 	<p>Application/Control No.</p> <p>10626300</p>	<p>Applicant(s)/Patent Under Reexamination</p> <p>RICHIE ET AL.</p>
	<p>Examiner</p> <p>Kitov, Zeev</p>	<p>Art Unit</p> <p>2836</p>

Class	SubClass	Date	Examiner
361	213	09/20/2006	ZK
	229	09/20/2006	ZK
	235	09/20/2006	ZK

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<b><i>Interference Searched</i></b>  	Application/Control No.  10626300	Applicant(s)/Patent Under Reexamination  RICHIE ET AL.
	Examiner Kitov, Zeev	Art Unit 2836

Class	SubClass	Date	Examiner
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